CA3060A/...

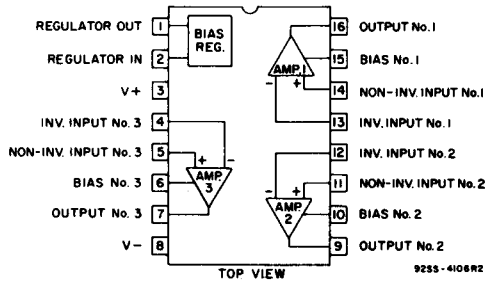
Operational Transconductance Amplifier Arrays

The CA3060 Slash (/) Series type is supplied in the 16-lead dual-in-line ceramic package (D suffix).

TABLE A. POST BURN-IN, FINAL ELECTRICAL AND GROUP A SAMPLING TESTS

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS						UNITS
			MIN.			MAX.			
			-55°C	+25°C	+125°C	-55°C	+25°C	+125°C	
Input Offset Voltage	V_{IO}	V+ = +15 V, V- = -15 V	-6	-5	-6	+6	+5	+6	mV
Input Bias Current	I_{IB}	I_{ABC} = 100 μA	—	—	—	10000	5000	10000	nA
Input Offset Current	I_{IO}		-2000	-1000	-2000	2000	1000	2000	nA
Input Offset Voltage Sensitivity	$\Delta V_{IO}/\Delta V+$		-150	-150	-150	+150	+150	+150	μV/V
	$\Delta V_{IO}/\Delta V-$		-150	-150	-150	+150	+150	+150	μV/V
Peak Output Voltage	$V_{OM}+$		12	12	12	15	15	15	V
Peak Output Voltage	$V_{OM}-$		-15	-15	-15	-12	-12	-12	V
Amplifier Supply Current	I_A		—	—	—	1500	1200	1500	μA
Zener Bias Regulator									
Zener Voltage	V_Z	I_Z = 100 μA	5.9	6.2	5.9	8.2	7.9	8.2	V
Zener Voltage	V_Z	I_Z = 1 mA	5.9	6.3	6.0	8.2	8.0	8.2	V

* (each ampl.)



Functional block diagram.

TABLE B. DELTA LIMITS *at $T_A = 25°C$, $V^+ = +15$ V, $V^- = -15$ V, $I_{ABC} = 100\ \mu A$ (/1 only)*

CHARACTERISTIC		LIMITS MAX.Δ	UNITS
Input Offset Voltage	V_{IO}	±0.15	mV
Input Offset Current	I_{IO}	±50	nA
Input Bias Current	I_{IB}	±250	nA

TABLE C. GROUPS C AND D END-POINT TESTS *at $T_A = 25°C$, $V^+ = +15$ V, $V^- = -15$ V, $I_{ABC} = 100\ \mu A$*

CHARACTERISTIC		LIMITS MIN.	LIMITS MAX.	UNITS
Input Offset Voltage	V_{IO}	-10	+10	mV
Input Offset Current	I_{IO}	-2000	+2000	nA
Input Bias Current	I_{IB}	—	9000	nA
Peak Output Voltage	V_{OM+}	10	15	V
Peak Output Voltage	V_{OM-}	-15	-10	V
Amplifier Supply Current (each amp)	I_A	—	1500	μA

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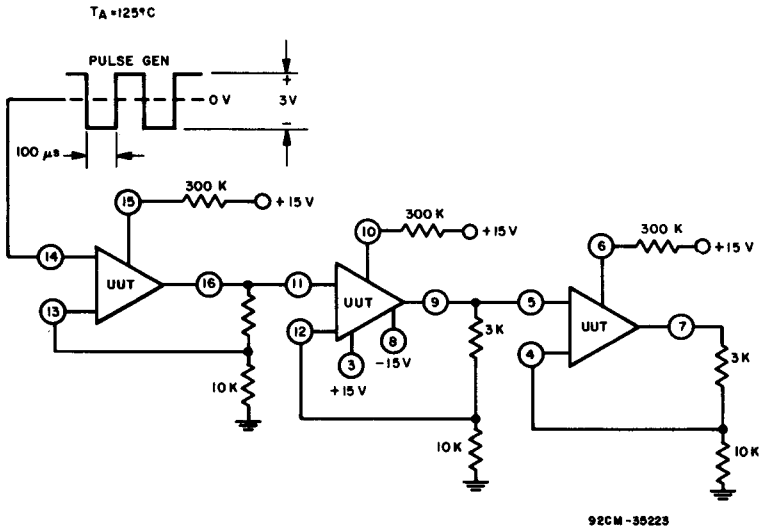

Burn-in and operating life-test circuit.